

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/517,026	LECLAIR, PHILIPPE
Examiner	Art Unit	
Jason M. Perilla	2611	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East USPAT/USPGPUB	7/9/2007	JP
Inventor Name Search	7/9/2007	JP
NPL Search IEEE Explore	7/9/2007	JP